



Call for Papers

IEEE Open Journal of Instrumentation and Measurement (IEEE OJIM)

Special Section on

Fault Tolerant Measurement Systems

Fault-Tolerant Measurement Systems represent a diverse field that spans numerous areas of science and engineering, significantly impacting a wide range of industries. In today's context, improving quality, reliability, and safety through instrumentation and measurement has become essential. These tasks play a critical role in various applications including energy, transportation, information and communication technology, logistics, and more.

This *Special Section*, in the IEEE OJIM focuses on recent advancements in Fault Tolerant Measurement Systems for reliable application. The scope includes the methods and instrument/device development, advances in models and algorithms for measurement, components and system testing, fault diagnosis, condition monitoring, risk and safety assessment as well as management methodology that allow for reliable, safe, and sustainable devices.

The topics for this special section include, but are not limited to, the following:

- Reliable computing for instrumentation and measurement
- Reliable architecture for instrumentation
- Reliable computing for instrumentation and distributed sensors in challenging environments
- Condition monitoring and maintenance of industrial process, plants, and complex systems
- Measurements and techniques for fault detection and diagnosis
- Measurements, methods, and instrumentation for evaluation of reliability, availability, maintainability and safety (RAMS), risk assessment and management

Each Submitted paper will go through a rigorous review process consistent with the IEEE OJIM requirements. The Open-Access [Article Processing Charge](#) (APC) of \$2,075 (in 2025) will be *waived* for accepted papers. Please note that the [Overlength Page Charge](#) fee will still be charged for papers longer than eight pages.

Papers will be published as they are accepted, and the Special Section is intended to be published in the latter part of 2025, consistent with the following Schedule:

Deadlines

Submission: April 30, 2025

First Decision: June 15, 2025

Final Decision: August 15, 2025

Publication Volume: Volume #4, 2025

For more information and submission instructions, please visit OJIM's website:

<https://iee-ims.org/publication/ieee-ojim/about>

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